

JAN 13 2006

Docket No.: 2328-062

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**PATENT**

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of

Inventor(s): DHINDSA, Rajinder et al.

U.S. Patent Application No. 10/645,665

Filed: August 22, 2003

For: MULTIPLE FREQUENCY PLASMA ETCH REACTOR

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:  
: Confirmation No. 8414  
:  
: Group Art Unit: 1762  
:  
: Examiner: Marianne L. PADGETT

**INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

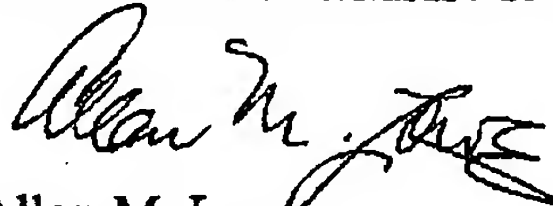
Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed before the mailing date of a first Office Action on the merits. No certification or fee is required.

Respectfully submitted,

**LOWE HAUPTMAN & BERNER, LLP**

  
Allan M. Lowe  
Registration No. 19,641

1700 Diagonal Road, Suite 310  
Alexandria, Virginia 22314  
(703) 684-1111  
Facsimile: (703) 518-5499

**Date: January 13, 2006**

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Sheet 1 of 1

<b>INFORMATION DISCLOSURE CITATION IN AN APPLICATION  (PTO-1449)</b>				ATTY. DOCKET NO. 2328-062		U.S. PATENT APPLICATION NO. 10/645,665	
				APPLICANT <b>DHINDSA, Rajinder et al.</b>			
				FILING DATE August 22, 2003		GROUP 1762	
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
	6,849,154	02-2005	Nagahata et al.				
	6,485,602	11-2002	Hirose				
	6,153,068	11-2000	Ohmi et al.				
	6,071,372	06-2000	Ye et al.				
	5,897,713	04-1999	Tomioka et al.				
	5,556,549	09-1996	Patrick et al.				
	6,387,287	05-2002	Hung et al.				
	6,506,674	01-2003	Ikeda et al.				
	6,303,510	10-2001	Chien et al.				
	6,127,278	10-2000	Wang et al.				
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
OTHER ART (including Author, Title, Date, Pertinent Pages, etc.)							
EXAMINER				DATE CONSIDERED			

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.